Search Notes

Application/Control No.	Applicant(s)/Patent (Reexamination	ınder
09/995,108	HEINEKE ET AL.	
Examiner	Art Unit	
Loclio Bascal	2622	

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Class	Subclass	Date	Examiner
398	9,22,24,13 5-139	3/21/2005	LP
438	7,14-18	3/21/2005	LP
385	14,24	3/21/2005	LP

INTERFERENCE SEARCHED			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR